

What Is Claimed Is:

1. A system for WAT (Wafer Acceptance Test) configuration, comprising:

an input/output device receiving a first WAT model and
5 qualification criteria;

a storage device storing a preset WAT model and
qualification criteria; and

a processor modifying the preset WAT model according to the
first WAT model to generate a second WAT model, and
10 modifying the preset qualification criteria
according to the first qualification criteria to
generate qualification criteria.

2. The system of claim 1, further comprising a WAT
control mechanism transforming the second WAT model into a test
15 program operable on a selected target WAT platform.

3. The system of claim 1, further comprising a quality
control mechanism performing a quality examination according to
the second qualification criteria.

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4. The system of claim 1, further comprising an engineering support mechanism generating a report according to the second qualification criteria, WAT results, and quality examination results.

5 5. The system of claim 1, wherein the WAT model specifies number and arrangement of test sites in a WAT.

6. The system of claim 1, wherein the qualification criteria specifies a key parameter.

7. The system of claim 1, wherein the qualification
10 criteria specifies an acceptable quality level.

8. A method for WAT (Wafer Acceptance Test) configuration, comprising:

providing a preset WAT model and qualification criteria;

providing a first WAT model and qualification criteria;

15 modifying the preset WAT model according to the first WAT
model to generate a second WAT model;

modifying the preset qualification criteria according to
the first qualification criteria to generate second
qualification criteria.

9. The method of claim 8, further comprising
5 transforming the second WAT model into a test program operable
on a selected target WAT platform.

10. A method of claim 8, further comprising performing a
quality examination based on the second qualification criteria.

11. The method of claim 8, further comprising generating
10 a quality report according to results of the WAT and the quality
examination.

12. The method of claim 8, wherein the WAT model specifies
number and arrangement of test sites in WAT.

13. The method of claim 8, wherein the qualification
15 criteria specifies a key parameter.

14. The method of claim 8, wherein the qualification
criteria specifies an acceptable quality level.

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15. A computer readable storage medium storing a computer program providing a method for WAT (Wafer Acceptance Test) configuration, comprising:

receiving preset test and qualification criteria;

5 receiving first test and qualification criteria;

modifying the preset WAT model according to the first WAT

model to generate a second WAT model;

modifying the preset qualification criteria according to

the first qualification criteria to generate second

10 qualification criteria.

16. The storage medium of Claim 15, wherein the method further comprises transforming the second WAT model into a test program operable on a selected target WAT platform.

17. The storage medium of Claim 15, wherein the method
15 further comprises performing a quality examination based on the second qualification criteria.

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18. The storage medium of Claim 15, wherein the method further comprises generating a quality report according to results of the WAT and the quality examination.

19. The storage medium of Claim 15, wherein the WAT model
5 specifies the number and arrangement of test sites in a WAT.

20. The storage medium of Claim 15, wherein the qualification criteria specifies a key parameter.

21. The storage medium of Claim 15, wherein the qualification criteria specifies an acceptable quality level.

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